

TYPES A5T4026 THRU A5T4029, A8T4026 THRU A8T4029 P-N-P SILICON TRANSISTORS

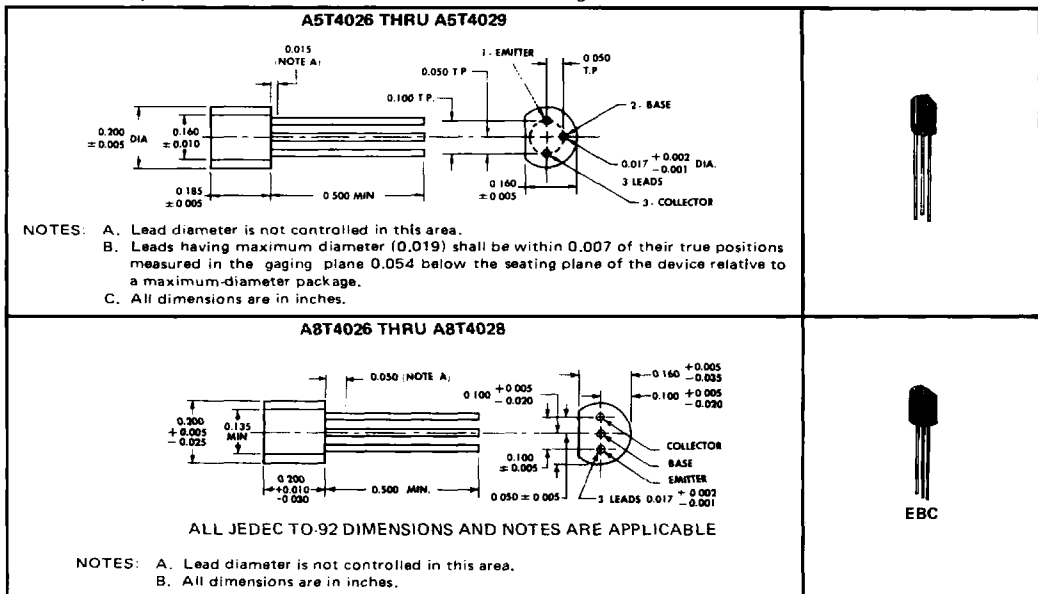
BULLETIN NO. DL-S 7312002, MARCH 1973

SELECT† TRANSISTORS‡ FOR GENERAL PURPOSE APPLICATIONS

- High $V(BR)_{CEO}$. . . 80 V Min (A5T4027, A5T4029, A8T4027, A8T4029)
- High Current Capability . . . 1 A
- Rugged One-Piece Construction with In-Line Leads or Standard TO-18 100-mil Pin-Circle Configuration

mechanical data

These transistors are encapsulated in a plastic compound specifically designed for this purpose, using a highly mechanized process developed by Texas Instruments. This case will withstand soldering temperatures without deformation. These devices exhibit stable characteristics under high-humidity conditions and are capable of meeting MIL-STD-202C, Method 106B. The transistors are insensitive to light.



absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)

	A5T4026	A5T4027	A5T4028	A5T4029	A8T4026	A8T4027	A8T4028	A8T4029
Collector-Base Voltage	-60 V	-80 V	-60 V	-80 V	-60 V	-80 V	-60 V	-80 V
Collector-Emitter Voltage (See Note 1)	-60 V	-80 V	-60 V	-80 V	-60 V	-80 V	-60 V	-80 V
Emitter-Base Voltage	-5 V	-5 V	-5 V	-5 V	-5 V	-5 V	-5 V	-5 V
Continuous Collector Current	← -1 A →							
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 2)	← 625 mW →							
Continuous Device Dissipation at (or below) 25°C Lead Temperature (See Note 3)	← 1.25 W →							
Storage Temperature Range	← -65°C to 150°C →							
Lead Temperature 1/16 Inch from Case for 10 Seconds	← 260°C →							

- NOTES: 1. These values apply between 0 and 10 mA collector current when the base-emitter diode is open-circuited.
 2. Derate linearly to 150°C free-air temperature at the rate of 5 mW/°C.
 3. Derate linearly to 150°C lead temperature at the rate of 10 mW/°C. Lead temperature is measured on the collector lead 1/16 inch from the case.

†Trademark of Texas Instruments
 ‡U.S. Patent No. 3,439,238

USES CHIP P16

TYPES A5T4026 THRU A5T4029, A8T4026 THRU A8T4029 P-N-P SILICON TRANSISTORS

electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	A5T4026 A8T4026		A5T4027 A8T4027		A5T4028 A8T4028		A5T4029 A8T4029		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
$V_{(BR)CBO}$ Collector-Base Breakdown Voltage	$I_C = -10 \mu A, I_E = 0$	-60		-80		-60		-80		V
$V_{(BR)CEO}$ Collector-Emitter Breakdown Voltage	$I_C = -10 \text{ mA}, I_B = 0,$ See Note 4	-60		-80		-60		-80		V
$V_{(BR)EBO}$ Emitter-Base Breakdown Voltage	$I_E = -10 \mu A, I_C = 0$	-5		-5		-5		-5		V
I_{CBO} Collector Cutoff Current	$V_{CB} = -50 \text{ V}, I_E = 0$		-50				-50			nA
	$V_{CB} = -60 \text{ V}, I_E = 0$				-50				-50	nA
	$V_{CB} = -50 \text{ V}, I_E = 0,$ $T_A = 100^\circ \text{C}$		-5				-5			μA
	$V_{CB} = -60 \text{ V}, I_E = 0,$ $T_A = 100^\circ \text{C}$				-5				-5	μA
I_{EBO} Emitter Cutoff Current	$V_{EB} = -5 \text{ V}, I_C = 0$		-10		-10		-10		-10	μA
h_{FE} Static Forward Current Transfer Ratio	$V_{CE} = -5 \text{ V}, I_C = -100 \mu A$	30		30		75		75		
	$V_{CE} = -5 \text{ V}, I_C = -100 \text{ mA}$	40	120	40	120	100	300	100	300	
	$V_{CE} = -5 \text{ V}, I_C = -100 \text{ mA},$ $T_A = -55^\circ \text{C}$	15		15		40		40		
	$V_{CE} = -5 \text{ V}, I_C = -500 \text{ mA}$	25		25		70		70		
	$V_{CE} = -5 \text{ V}, I_C = -1 \text{ A}$	15		10		40		25		
V_{BE} Base-Emitter Voltage	$I_B = -15 \text{ mA}, I_C = -150 \text{ mA}$		-0.9		-0.9		-0.9		-0.9	V
	$V_{CE} = -0.5 \text{ V}, I_C = -500 \text{ mA}$		-1.1		-1.1		-1.1		-1.1	V
	$V_{CE} = -1 \text{ V}, I_C = -1 \text{ A}$		-1.2				-1.2			V
$V_{CE(sat)}$ Collector-Emitter Saturation Voltage	$I_B = -15 \text{ mA}, I_C = -150 \text{ mA}$		-0.15		-0.15		-0.15		-0.15	V
	$I_B = -50 \text{ mA}, I_C = -500 \text{ mA}$		-0.5		-0.5		-0.5		-0.5	V
	$I_B = -100 \text{ mA}, I_C = -1 \text{ A}$		-1				-1			V
$ h_{fe} $ Small-Signal Common-Emitter Forward Current Transfer Ratio	$V_{CE} = -10 \text{ V}, I_C = -50 \text{ mA},$ $f = 100 \text{ MHz}$	1	4	1	4	1.5	5	1.5	5	
C_{cb} Collector-Base Capacitance	$V_{CB} = -10 \text{ V}, I_E = 0,$ $f = 1 \text{ MHz},$ See Note 5		20		20		20		20	pF
C_{ibo} Common-Base Open-Circuit Input Capacitance	$V_{EB} = -0.5 \text{ V}, I_C = 0,$ $f = 1 \text{ MHz}$		110		110		110		110	pF

NOTES: 4. These parameters must be measured using pulse techniques. $t_w = 300 \mu s,$ duty cycle $\leq 2\%$.

5. C_{cb} measurement employs a three-terminal capacitance bridge incorporating a guard circuit. The emitter is connected to the guard terminal of the bridge.

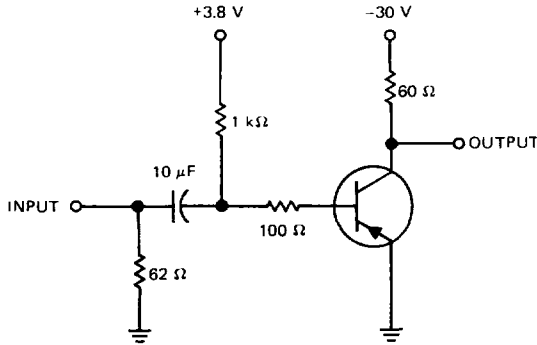
TYPES A5T4026 THRU A5T4029, A8T4026 THRU A8T4029 P-N-P SILICON TRANSISTORS

switching characteristics at 25°C free-air temperature

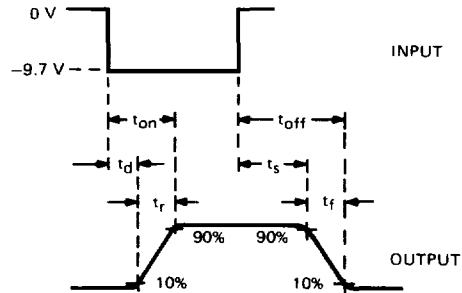
PARAMETER	TEST CONDITIONS†	MAX	UNIT
t_{on} Turn-On Time	$V_{CC} = -30$ V, $I_C = -500$ mA,	100	ns
t_s Storage Time	$I_B(1) = -50$ mA, $I_B(2) = 50$ mA,	350	ns
t_f Fall Time	$V_{BE(off)} = 3.8$ V, See Figure 1	50	ns

† Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.

PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT



(See Notes a and b)
VOLTAGE WAVEFORMS

- NOTES: a. The input waveform is supplied by a generator with the following characteristics: $Z_{out} = 50 \Omega$, $t_r \leq 20$ ns, $t_f \leq 20$ ns, $t_w \approx 10 \mu$ s, duty cycle $\leq 2\%$.
b. Waveforms are monitored on an oscilloscope with the following characteristics: $t_r \approx 10$ ns, $R_{in} \geq 100$ k Ω .

FIGURE 1—500-mA SWITCHING TIMES

THERMAL INFORMATION

FREE-AIR TEMPERATURE
DISSIPATION DERATING CURVE

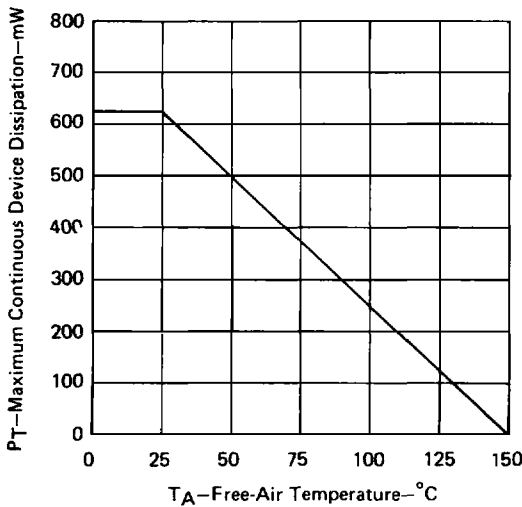


FIGURE 2

LEAD TEMPERATURE
DISSIPATION DERATING CURVE

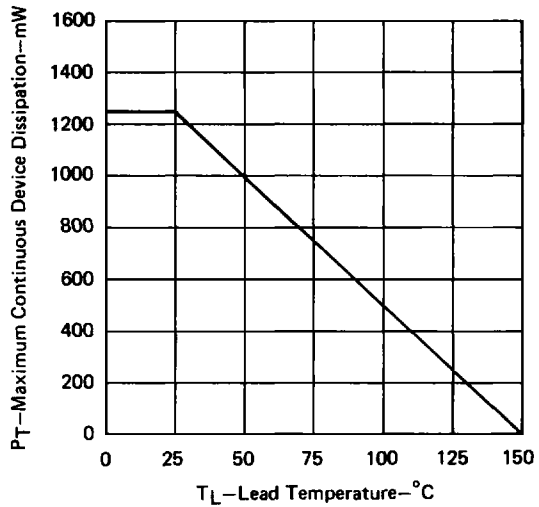


FIGURE 3